INTERNATIONAL RELIABILITY PHYSICS SYMPOSIUM

SUNDAY, MARCH 30, 2003

TUTORIAL NOTES

Dan Barton, Chair

Hyatt Regency Dallas at Reunion
Dallas, Texas

Topic 111. INTRODUCTION TO SEMICONDUCTOR RELIABILITY
Vijay Reddy, Texas Instruments (111.1–74) 111

Topic 112. INTRODUCTION TO PREDICTIVE WAFER LEVEL RELIABILITY
Eric Snyder, Sandia Technologies (112.1–36) 112

Topic 121. ESD BASICS
Charvaka Duvvury, Texas Instruments (121.1–22) 121

Topic 122. ESD TESTING AND FAILURE ANALYSIS FOR SEMICONDUCTOR IC'S
Jonathan Brodsky, Texas Instruments (122.1–22) 122

Topic 123. ESD HIGH CURRENT PHENOMENA, MODELING AND PROCESS EFFECTS
Gianluca Boselli, Texas Instruments (123.1–36)........................ 123

Topic 124. ADVANCED ESD PROTECTION DESIGN
Charvaka Duvvury, Texas Instruments (124.1–32) 124

Topic 131. PROBLEMS AND SOLUTIONS FOR FA ON ADVANCED MICROELECTRONIC CIRCUITS
Chris Henderson, Sandia National Laboratories (131.1–24) 131

Topic 132. OPTICAL TOOLS FOR IC FAILURE ANALYSIS
Ed Cole,Jr., Sandia National Laboratories (132.1–28)............. 132